

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5	((714/25,30,43,44,724,728,733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/05 10:46
S10 5	5	((714/25,30,43,44,724,728,733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/05 10:45
S88	5	((714/25,30,43,44,724,728,733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/26 12:01

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S10 4	5	((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)) not ((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/04 16:19
S10 3	1	"4503537".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:20
S10 2	1	"5230000".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:19
S10 1	1	"5260946".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:18
S10 0	1	"5659312".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:18
S99	1	"5706296".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:16
S98	1	"6119250".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:15
S97	1	"6313656".PN.	USPAT; USOCR	OR	ON	2005/03/04 13:15
S96	2	"6675322".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/04 13:15
S95	1	"5381421".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:10
S94	1	"5400057".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:09
S93	1	"5225774".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:08
S92	1	"5230001".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:07
S91	1	"5459733".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:06
S90	1	"5621739".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:06

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S89	1	"5869983".PN.	USPAT; USOCR	OR	ON	2005/03/04 10:05
S13	9	(((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 16:47
S87	7523	(714/25,30,43,44,724,728,733-735, 738,739,742).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 16:41
S79	147	((power voltage) near4 supply) same ((buffer I/O VDD\$4) near4 ring)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 16:40
S86	1	"3676777".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:03
S85	1	"4862075".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:03
S84	1	"5101150".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:03
S83	1	"5124638".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:03
S82	1	"5130646".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:02
S81	1	"5132613".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:02
S80	1	"5177437".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 15:01
S78	44	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference same supply	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 14:07

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S68	1167	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 14:07
S77	133	(((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:59
S74	90	(((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and test\$3 near4 (IC "integrated circuit" semiconductor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:59
S76	2	("low voltage differential signals" LVDS) same PLL and LFSR	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:49
S75	106	("low voltage differential signals" LVDS) same PLL	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:49
S55	596	("low voltage differential signals" LVDS "double data rate" DDR) near4 interface	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:48
S73	5	(((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and ((DUT load) near4 board)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:23
S69	3	(((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and DUT near4 board	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:16
S72	1	"4117400".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 13:14
S71	1	"4339673".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 13:14
S70	1	"4929888".PN.	US-PGPUB; USPAT	OR	ON	2004/07/22 13:14

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S65	2221	(separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 13:03
S67	50	((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and self-test\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 10:49
S66	1	((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and ("low voltage differential signals" LVDS "double data rate" DDR) same self-test\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 10:48
S64	5	("low voltage differential signals" LVDS "double data rate" DDR) near4 self-test\$7 and (volt\$3 power)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/22 10:47
S63	51	((I/O near4 interface) same self-test\$7) not (((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator")))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:11
S62	11	((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:11
S61	0	((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:08
S58	3	("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:08

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S60	62	(I/O near4 interface) same self-test\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:06
S48	1	((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("multiple input shift register" MISR)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 16:05
S59	2	(DE-19832307\$ DE-19901460\$).did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:59
S57	13	("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:28
S56	3	("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)) and ("multiple input shift register" MISR signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:28
S54	26	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR) and ("multiple input shift register" MISR signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:25
S53	31	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:11
S52	13	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:11
S51	1	(bidirectional\$2 bi-directional\$2) same (interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 14:09

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S50	4	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature compact\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 13:56
S49	3	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 13:55
S47	1	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 13:47
S14	84	((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 13:46
S46	1	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and MISR	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/21 13:45
S45	12	(US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.	US-PGPUB; USPAT	OR	OFF	2004/07/21 13:44

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S44	1	"5230001".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:40
S43	1	"5459733".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:39
S42	1	"5621739".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:39
S41	1	"5869983".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:39
S40	1	"5321277".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:28
S39	1	"5321277".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:28
S38	1	"5416409".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:28
S37	1	"5423050".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:28
S36	1	"5416409".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:27
S35	1	"5423050".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:27
S34	1	"5444715".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:26
S33	1	"5473617".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:26
S32	1	"5535331".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:25
S31	1	"4646297".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:15
S30	1	"5436908".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:15
S29	1	"5578938".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:15
S28	1	"5894226".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:15
S27	1	"5991890".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:15
S26	1	"6016566".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:14
S25	1	"5619512".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:14
S24	1	"6105156".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:13
S23	1	"6112321".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:13

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S22	1	"6114866".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:12
S21	1	"6175939".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:12
S20	1	"6223312".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:12
S19	1	"6275057".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:12
S18	1	"6282680".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:10
S17	1	"6347387".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:09
S16	1	"6397363".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:08
S15	1	"6477674".PN.	US-PGPUB; USPAT	OR	ON	2004/07/21 10:08
S12	0	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:30
S11	0	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:30

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S10	51	((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:30
S8	42	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:25
S9	626	((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:24
S6	435	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:24
S7	1	(((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) and (\$6random near6 generat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 16:06
S5	32	((interface near4 (circuit device)) and (Britt Harris Dooley).XA.) and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 15:58
S4	94	(interface near4 (circuit device)) and (Britt Harris Dooley).XA.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 15:19
S3	70	(interface and (Britt Harris Dooley).XA.) and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 15:18

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S2	44538	"714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 15:18
S1	370	interface and (Britt Harris Dooley). XA.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/20 15:18